

## Overview

The purpose of this notification is to announce that Holt Integrated Circuits has made a Die Revision Change to the HI-8588PSxx-10 Product.

## Description

Holt Integrated Circuits is implementing a design change to improve the yield of the HI-8588PSxx-10 inputs when subjected to transient voltages greater than +/-80V at room temperature.

This improvement will result in a die revision change for the HI-8588PSxx-10 product from Revision K to Revision T.

There is no change to Fit, Form, Function, Quality or Reliability of these devices. The products will be fully compliant to all published datasheet specifications of HI-8588-10 Datasheet (DS8588-10 Rev. E). Quality and Reliability will remain at the highest standards already demonstrated with Holt Integrated Circuits' existing products.

## Reason

The purpose of this design change will eliminate an opening in the pad mask between the two inputs. This removal prevents the possibility of any mold compound or foreign material from being in the opening between RINA and RINB and therefore eliminating the source of yield loss activated at high voltages greater than +/-80V.

## Products Affected

**HI-8588PSI-10**      **HI-8588PSIF-10**  
**HI-8588PST-10**    **HI-8588PSTF-10**  
**HI-8588PSM-10**    **HI-8588PSMF-10**

## Traceability

Customers that order parts with the following Holt Manufacturing Number Order Codes will receive only parts made with die revision T assembled with date code 1430 and after.

**HI-8588PSI-10A**    **HI-8588PSIF-10A**  
**HI-8588PST-10A**   **HI-8588PSTF-10A**  
**HI-8588PSM-10A**   **HI-8588PSMF-10A**

A new Holt manufacturing number order code or date code of 1430 and after will facilitate part traceability. Part marking for this product will not change as result of this PCN. All parts will be shipped starting September 1, 2014.

## Qualification Data

Reliability Test	Requirement	Comment
Device Characterization	Final Test yield analysis over -55°C and +125°C temperature extremes.	
+/-80V Stress Test	Final Test yield analysis at room	Zero fails to pass
Lightning Test	DO-160 Section 22 Level 3 WF3 pin injection	25 out of 25 to pass

## Response

**Note:** In accordance with JESD46-D, this change is deemed accepted by the customer if no acknowledgement is received within 30 days from this notice.

No response is required. For additional information or questions, please contact:

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## Revision History

The following table shows the revision history for this document.

Date	Version	Revision Description
8/01/14	1.0	Initial Release